

Ali Pourkeramati

Chief Technology Officer Spansion Inc.

Breaking Down the Barriers:

Bringing Disruptive Memory Technology to Market





FLASH FORWARD

How Radical Should Changes Be?

Disruptive Interrupt the normal course of Technology

Evolutionary.

Continue to change from a lower to a higher, more complex, or better state of Technology



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New Applications, New Infrastructure and New Market

OR

Improve the existing applications

More applications without creating
 a new infrastructure



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How Disruptive Technology can be effective?

"In spite of the rare instances when disruptive technology has been successfully deployed in the memory industry, we operate under the assumption that it can and should be, without fully examining how to do it or even if we should."

> Spansion as one of the few companies that has successfully deployed a disruptive technology in the memory market.



Polarized Mainstream Memory Use

Defines infrastructure and ecosystem



Source: Gartner (February 2009)

* Excludes memory embedded in ASIC or ASSP components.



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Memory Attributes

Keep discrete or combine in one technology?



DRAM Volatile + Refresh Most expensive Very fast read & write

> Best for Real time code execution cache



NOR Non-volatile Low cost Fast read High reliability

Best for code storage and execution



NAND Non-volatile Lowest cost Fast write & erase

> Best for media storage



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Does Disruptive Technology = Disruptive Use?

Sometimes ... but then it takes much longer to ramp





Source: Spansion

Next-Generation Memory Specification

Table stakes to deliver "acceptable" system benefits

- Competitive cost
- Compatible with high-volume manufacturing techniques
- Architecture balance
 - Performance
 - High speed read
 - High speed program, erase/overwrite
 - Low power
- Reliability
 - Data retention
 - Endurance

"Acceptable" defined by the infrastructure

- What is required from the memory device
- What can be exploited by the system software and hardware



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Technology & Infrastructure Maturity

	Mature	Evolving	Disruptive (Near Term)	Disruptive (Long Term)
Technology	Floating Gate	Charge Trapping (e.g. MirrorBit®)	РСМ	Other RCM RRAM MRAM
Mass Market Maturity	20 years	7 years	Years Away	Many Years Away



Source: Spansion

Resistive Change Memory

Near term or long term technology solution?



- 1. 4-5F² MLC cell
- 2. Compact select device with sufficient drive current, e.g. vertical diode
- 3. Minimum pitch, fine-line, high conductivity interconnect in both directions



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Near Term: Phase Change Memory

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Challenges the industry has to overcome

	Issue	Risk	Comments
1	Performance: Programming speed	High	High current limits parallelism in programming
2	Manufacturability: Process complexity	High	Challenging integration with significant number of critical masking steps
3	Cost and Manu: Multi-level capability	High	Resistance drift challenges state placement
4	Cost Complexity vs. existing technology	High	SLC significantly more complex process
5	Cost Cell size	High	Compromises for shrink from 12F ²
6	Cost and Manu. Scalability	High	Select devices may not scale. GST area is already sub-lithographic
7	Bit alterability	Low	Truly disruptive for NVM



Charge Trapping: Innovation at the Cell – Evolution in the System



Disruptive Scalability



Source: Spansion estimates



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Evolutionary Ramp

New technology must be "acceptable" for the customer



MirrorBit[®] technology share of NOR segment



Source: Spansion

NOR Cell Size Scaling Example







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What It Takes to Make "It" Work!

- 0 0 0 0 0 0 0 0 0
- Intimate Technology, Design, Product Eng, Test Collaboration
 - New & old technology aren't the same Different mindset required
 - What works in the lab doesn't necessarily work in production
- Specific MirrorBit[®] technology design innovations

Advanced Program and Erase Algorithms	 Temperature and cell location compensation Compact, uniform cell distributions 	 Stabilizes cell behavior Optimizes data retention 	
Advanced Read	 Increases margin by reducing parasitic currents Opens up sensing window 		
Advanced Process	 Creating the highest tech 	nnique in process	



Charge Trapping Next Steps with MirrorBit[®] NAND Technology "Evolution of Technology"



The Technology

MirrorBit[®] NAND Technology



- SONOS-like cell structure
- Cells connected in NAND array
- Highly scalable
- SLC and MLC capable
- Leverages proprietary MirrorBit[®] charge trapping technology and manufacturing know-how
- Different technology but excellent process compatibility with MirrorBit NOR for production in same fabs



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Efficient Die Size



* Source: Spansion estimates of MirrorBit® NAND versus 4xnm Floating gate SLC NAND solutions



What Will the Future Look Like?

Moving closer to the ideal memory





What Will the Future Look Like?

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Moving closer to the ideal memory



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Conclusion

Existing industry is structured for evolution

- Even in Silicon Valley!
- Disruption can be risky for both customers and suppliers
- It takes a long time to create new Infrastructure in a new Eco-System

New technology is never adopted quickly

- Memory doesn't exist in a vacuum
- Even evolution takes a while
- Disruption needs H/W and S/W infrastructure to change

Tomorrow's technologies...

- Must be relevant and must be viable
- Must offer more than today's technology ... otherwise why change?





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